

**Issue Classification**

Application/Control No.

10602002

Applicant(s)/Patent Under Reexamination

LIM ET AL.

Examiner

Faulk, Devona E

Art Unit

2615

**ORIGINAL**

CLASS

SUBCLASS

381

104

**CROSS REFERENCE(S)**

CLASS

SUBCLASS (ONE SUBCLASS PER BLOCK)

381

107

109

102

106

**INTERNATIONAL CLASSIFICATION**

CLAIMED

NON-CLAIMED

H

0

3

G

3 / 00 (2006.01.01)

H

0

3

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7 / 00 (2006.01.01)

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0

3

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9 / 00 (2006.01.01)

Faulk, Devona E

9/13/2007

(Assistant Examiner)

(Date)

WIVIAN CHIN  
SUPERVISOR PATENT EXAMINER  
TECHNOLOGY CENTER 2200

Total Claims Allowed:

22

(Legal Instruments  
Examiner)

(Date)

(Primary Examiner)

(Date)

O.G. Print Claim(s)

1

O.G. Print Figure

2